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Tailoring of the thermal expansion of $\text{Cr}_2(\text{Al}_x\text{Ge}_{1-x})\text{C}$ phases

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Abstract

We report thermal expansion coefficients of the end members and solid-solution compounds in the $\text{Cr}_2(\text{Al}_x\text{Ge}_{1-x})\text{C}$ system. All samples studied were essentially phase-pure $\text{Cr}_2\text{Al}_x\text{Ge}_{1-x}\text{C}$ except the Cr_2GeC sample, which contained a substantial fraction of $\text{Cr}_5\text{Ge}_3\text{C}_x$. X-ray diffraction performed in the 25 to 800 °C temperature range shows that the in-plane thermal expansion remains essentially constant at about $14 \pm 1 \cdot 10^{-6} \text{ K}^{-1}$ irrespective of Al content. The thermal expansion of the c axis decreases monotonically from $17 \pm 1 \cdot 10^{-6} \text{ K}^{-1}$ for Cr_2GeC to $\sim 12 \pm 1 \cdot 10^{-6} \text{ K}^{-1}$ with increasing Al content. At around the $\text{Cr}_2(\text{Al}_{0.75}\text{Ge}_{0.25})\text{C}$ composition, the thermal expansion coefficients along the two directions are equal; a useful property to minimize thermal residual stresses. This study thus demonstrates that a solid-solution approach is a route for tuning a physical property like the thermal expansion. For completeness, we also include a structure description of the $\text{Cr}_5\text{Ge}_3\text{C}_x$ phase, which has been reported before but is not well documented. Its space group is $P6_3/mcm$ and its a and c lattice parameters are 7.14 Å and 4.88 Å, respectively. We also measured the thermal expansion coefficients of the $\text{Cr}_5\text{Ge}_3\text{C}_x$ phase. They are found to be $16.3 \cdot 10^{-6} \text{ K}^{-1}$ and $28.4 \cdot 10^{-6} \text{ K}^{-1}$ along the a and c axes, respectively. Thus, the thermal expansion coefficients of $\text{Cr}_5\text{Ge}_3\text{C}_x$ are highly anisotropic and considerably larger than those of the $\text{Cr}_2(\text{Al}_x\text{Ge}_{1-x})\text{C}$ phases.

Keywords: Annealing, MAX phases, thermal expansion, Rietveld refinement, solid solution

I. Introduction

The family of phases known as $M_{n+1}AX_n$ phases ($n = 1 - 3$, or ‘MAX phases’) are a group of ternary early transition-metal (M) carbides and nitrides (X) interleaved with a group 12-16 element (A) [1,2,3,4]. The MAX phases have been extensively studied not only in order to shed light on their unique combination of properties but also to explore their potential for numerous industrial applications (see review articles [1,2,3,4] and recent examples [5,6,7,8,9,10,11,12,13]). It has long been appreciated that a promising strategy to tailor properties is to form solid solutions on the M, A and/or X sites [1,2]. However, practical examples of such property tuning are scarce, essentially limited to oxidation studies where the excellent oxidation resistance of the alumina-forming MAX phases Ti_2AlC and Ti_3AlC_2 is retained also for solid solutions, e. g., $Ti_3(Si,Al)C_2$ [14,15,16,17]. Solid-solution studies have mostly focused on exploring solid solution hardening effects [18,19,20,21,22,23], the evolution of the unit cell structure [24,25] or the possibility to synthesize new MAX phases [26,27,28,29]. Interestingly, with a few possible exceptions [30,31,32], solid solution hardening of the MAX phases does in general not appear to be pronounced. This issue is particularly evident in the Ti_3AC_2 systems with $A = Si, Ge, Al, Sn$, where numerous investigations [18,19,33,34,35] have demonstrated that solid solution hardening is not operative in these systems, while one study claims the opposite [32]. To advance the field, there is therefore a strong need for clear experimental evidence of solid-solution engineering to steer inherent materials properties.

The thermal expansion coefficients (TECs) of the MAX phases mainly fall in the range of ≈ 5 to $14 \cdot 10^{-6} K^{-1}$ [36]. The anisotropies of the TECs are relatively small for the Ti-containing MAX phases and become progressively higher as the average number of valence electrons increase (i.e., for M elements from groups 5 and 6 in the periodic table). In general, not much work has been carried out

on the effects of solid solutions on TECs. At $8.7 \cdot 10^{-6} \text{ K}^{-1}$, the TECs of Ti_2AlC and Nb_2AlC are the same and marginally lower than that of their 50-50 solid solution at $8.9 \cdot 10^{-6} \text{ K}^{-1}$ [37]. Similarly, it has been reported that substituting Ge for Si in Ti_3SiC_2 did not substantially affect the TECs of a 50-50 Si-Ge solid solution relative to the end members [33].

The main purpose of this work is to use a solid solution approach to tailor the thermal expansions of Cr_2GeC and Cr_2AlC . The rationale for choosing these two compounds is that both have relatively high and, especially Cr_2GeC , anisotropic TECs. Solids with high and anisotropic TECs tend to develop residual strains upon cooling. In some cases the residual strains can be so high as to result in the total failure of the solid [38]. The TEC of Cr_2GeC has been determined by measuring the temperature dependence of the lattice parameters obtained by x-ray diffraction (XRD) of powders [39] and from high temperature neutron diffraction [40], and is the highest of the known MAX phases. Both sets of experimental results are listed in Table. 1. However, the agreement between the two is not as good as most other MAX phases [39]. In passing, it is worth noting that the calculated thermal expansion coefficient [41] is more than 30 % larger than the highest experimental value.

The TEC of Cr_2GeC is the highest among all known MAX phases with an expansion along the c axis higher than in the basal plane. In contrast, in Cr_2AlC (also listed in Table 1), expansion along a is higher than along c [39]. It is therefore reasonable to assume that somewhere along the composition domain the two thermal expansions should cross. One could thus obtain a solid with isotropic thermal expansion and ideally eliminate the issues with residual strain upon cooling.

To this end, we have synthesized a series of $\text{Cr}_2\text{Al}_x\text{Ge}_{1-x}\text{C}$ compounds ($x = 0; 0.25; 0.5; 0.75; 1$) and determined their structural parameters and thermal expansion coefficients from ambient temperature to $800 \text{ }^\circ\text{C}$ by *in-situ* XRD during annealing and Rietveld analysis of the data. Isotropic

thermal expansion is obtained around the composition of $\text{Cr}_2\text{Al}_{0.75}\text{Ge}_{0.25}\text{C}$. All samples studied were essentially phase-pure $\text{Cr}_2\text{Al}_x\text{Ge}_{1-x}\text{C}$ except for the Cr_2GeC sample, which contained a substantial fraction of $\text{Cr}_5\text{Ge}_3\text{C}_x$. This phase is isostructural with $\text{Ti}_5\text{Si}_3\text{C}_x$ and has been known since the 1960s [42]. Although occasionally observed [43,44], its structure is not well documented in the literature. For completeness, we therefore also include its description as determined from Rietveld refinement.

II. Experimental Details

Five $\text{Cr}_2\text{Al}_x\text{Ge}_{1-x}\text{C}$ compounds ($x = 0; 0.25; 0.5; 0.75; 1$) were synthesized using conventional powder metallurgy techniques. Powders of Cr, Al, Ge and C were weighed to obtain the nominal compositions: 2 Cr: 1.1xAl: 1.1(1-x) Ge and C. Al (325 mesh), Cr (particle size $<10 \mu\text{m}$) and Ge (100 mesh) powders are (Alfa Aesar) with a purities better than 99.5%, 99.8% and 99.999%, respectively. Erachem ensacco 250 granular powder (Chemwatch) was used as carbon powder. For all compositions, an excess of 10 wt.% Al and Ge was used to compensate for their loss by evaporation during the sintering process. The reactants were then mixed for 1 h in a shaker (TurbulaTM) and hand pressed (uniaxial cold compaction) to obtain cylinders, ~ 0.5 cm high and ~ 12 mm in diameter. The ~ 3 -g cylinders had an open porosity close to 40 %. The five samples were placed together in a graphite furnace (NaberthermTM GmbH, Lilienthal) and heated to 1400°C at $10^\circ\text{C}/\text{min}$ and held at that temperature for 4 h.

The room temperature XRD patterns were obtained on a mechanically polished face of the samples in a Bragg-Brentano geometry using $\text{Cu K}\alpha$ radiation. A Bruker D8 diffractometer operating at 40 kV and 40 mA was used. The 2θ range covered was 10 to 80° , with step intervals of 0.02° or 0.03° (2θ). Counting times between 5 s and 20 s for each angular step were used. To obtain the instrument

resolution function to account for the experimental broadening, an XRD pattern of a standard Cr₂O₃ powder (Standard NIST 600) was collected under the same geometrical conditions.

X-ray diffractograms in the 25 to 800 °C temperature range of the five samples were acquired under vacuum (2×10^{-4} Pa) in a second diffractometer (X'PERT Philips) operating at 45 kV and 40 mA. An angular step size of 0.04°, with a count time of 4 s for each step, was used for the acquisition of diffractograms in the 35-50° 2 θ range. The heights of the samples were adjusted prior to each X-ray measurement for consistent alignment. The setup is described in more detail elsewhere [45]. In short, the samples were placed on a resistively heated Ta filament with a calibrated Pt/Rh thermocouple clamped on the backside of the filament. A second Ta filament surrounding the sample was used to prevent temperature gradients.

Rietveld refinement of each diffractogram was performed using the Materials Analysis Using Diffraction (MAUD) software [46]. Such refinement resulted in precise determination of the unit-cell parameters at every temperature. The errors are estimated to be generally lower than $5 \cdot 10^{-4}$ Å or $2 \cdot 10^{-3}$ Å for the a and c lattice parameters, respectively. These uncertainties in turn were used to determine the uncertainties in the results presented herein. The z parameter of the Cr atoms, z_{Cr} (z or z_M in more general notation), in the unit cell was also deduced from Rietveld refinement of the diffractograms at room temperature. In this case, the error is estimated to be $< 5 \cdot 10^{-4}$, this last value being used as the uncertainty for the z values reported here.

The following equations were used to calculate the distortion parameters and the distance between the atoms (see Ref. [47]). Note that these equations are only valid for a M₂AX phase and are different for M₃AX₂ and M₄AX₃ phases. Distortion factor of the octahedron:

$$O_d = \frac{\sqrt{3}}{2 \sqrt{4 z_M^2 \left(\frac{c}{a}\right)^2 + \frac{1}{12}}} \quad (\text{eq. 1})$$

Distortion factor of the trigonal prisms:

$$P_d = \frac{1}{\sqrt{\frac{1}{3} + \left(\frac{1}{4} - z_M\right)^2 \left(\frac{c}{a}\right)^2}} \quad (\text{eq. 2})$$

Distance between M and A atoms:

$$d_{M-A} = \sqrt{\frac{a^2}{3} + c^2 \left(z_M - \frac{1}{4}\right)^2} \quad (\text{eq. 3})$$

Distance between M and X atoms:

$$d_{M-X} = \sqrt{\frac{a^2}{3} + c^2 z_M^2} \quad (\text{eq. 4})$$

III. Results

The X-ray diffractograms of the samples tested are shown in Fig. 1. As previously mentioned, with the exception of Cr₂GeC (Fig. 1a), all other samples are predominantly single-phase. Rietveld analysis of the Cr₂GeC diffractograms showed the presence of about 41 wt. % Cr₅Ge₃C_x, a phase first reported by Jeitschko et al. [42]. Since the samples were porous and the lattice parameters were obtained from the Cr₂GeC peaks, the presence of this relatively large amount of secondary phase does not invalidate the results as evidenced by the good agreement in the TECs obtained here and those of Scabarozzi et al. [39]. Why those of Lane et al. [40] are different is discussed below.

Figures 2a and b show the compositional dependence of the a and c lattice parameters, respectively. These results show that the c parameter increases with increasing Al content (Fig. 2a) while the a parameter decreases (Fig. 2b). Figure 2c shows the relative changes in a , c , c/a and unit cell volumes, V_{uc} , as a function of increasing Al content x . From these results it is clear that while c and c/a increase with x , V_{uc} remains essentially constant and the a lattice parameter decreases. The z parameter - the height position of Cr atoms in the unit cell - also monotonically increases with increasing Al-content (Fig. 2d).

Furthermore, making use of the values of a , c and z one can calculate the octahedral, O_d , and trigonal prisms, P_d , distortion parameters, as well as the distances between the Cr and Al or Cr and C atoms (equations (1-4)). Figures 2e and 2f show the results of these calculations. Strong distortions of the octahedral and trigonal prism sites are obtained for Cr₂GeC ($O_d \approx 1.12$; $P_d \approx 1.16$). The distortions, however, decrease with increasing Al content in the solid solution. As seen in Fig. 2f, the distance between the Cr and C atoms only weakly depends on the A element. On the contrary, a slight increase of the Cr-A distance is found when one progressively replaces Ge by Al.

In figures 3a and b, the temperature dependencies of the a and c lattice parameters, respectively, are plotted as a function of composition. These results were least-squares-fitted and converted to TECs along the a and c directions - α_a and α_c - respectively. The TECs are listed in Table 1 and plotted in Fig. 3c as a function of composition. From these results it is clear that the effect of increasing the Al-content on α_c is higher than on α_a , the latter remaining almost constant. Significantly, the two values are equal around the $\text{Cr}_2(\text{Al}_{0.75}\text{Ge}_{0.25})\text{C}$ composition.

As noted above, our Cr_2GeC samples contained a large (~40 wt. %) phase fraction of $\text{Cr}_5\text{Ge}_3\text{C}_x$ phase. Jeitschko et al. [42] reported this phase and found it to be isostructural to $\text{Ti}_5\text{Si}_3\text{C}_x$ with space group $P6_3/mcm$ but without presenting the complete structure description. Here, we confirm this structure. For completeness, the structural parameters of $\text{Cr}_5\text{Ge}_3\text{C}_x$ determined from the Rietveld refinement are listed in Table 2. The occupancy of all sites is assumed to be 1. This may not be valid for the C sites, but virtually no difference in the refinement is obtained by allowing the C occupancy to vary because of the low scattering factor of the light C atoms that thus have a limited contribution to the diffraction. Thus, a conclusive determination of the C occupancy is not possible. At room temperature, the a and c lattice parameters were found to be 7.14 Å and 4.88 Å, respectively. Figure 4 shows the evolution of the a and c lattice parameters with temperature. The thermal expansion coefficients of the $\text{Cr}_5\text{Ge}_3\text{C}_x$ phase, listed in Table 1, are high and quite anisotropic. For comparison, the isostructural $\text{Ti}_5\text{Si}_3\text{C}_x$ phase has thermal expansion coefficients $\alpha_a = 9.4 \cdot 10^{-6} \text{ K}^{-1}$ and $\alpha_c = 17.8 \cdot 10^{-6} \text{ K}^{-1}$ [48].

IV. Discussion

The most important result of this work is the possibility of compositionally fine-tuning the TECs α_a and α_c so as to render them virtually equal (i.e., isotropic). For all intents and purposes, it is reasonable to assume that the $\text{Cr}_2(\text{Al}_{0.75},\text{Ge}_{0.25})\text{C}$ composition would respond to temperature variations as if it were a cubic solid. The most important benefit of this feature is the absence of residual stresses at room temperature when cooling from higher temperatures.

In a recent paper on the thermal properties of Cr_2GeC [40] it was conceded that the reason the TECs obtained from XRD were larger than those obtained from neutron diffraction was unclear. One possibility, always present, is sample-to-sample variations. Other possibilities are secondary phases and effects of non-stoichiometry, the latter known to occur for several other MAX phases [25,49]. However, our present TEC results are similar to those of Scabarozzi et al. [39]. It is therefore unlikely that the discrepancies are due to sample-to-sample variations. The variations must thus be traced to the method of investigation. In contradistinction to the neutron-diffraction work [40] where a *bulk* dense sample was used, here a highly porous sample was used instead. Given the high anisotropies of the TECs it is reasonable to assume that upon cooling of the bulk sample micro-strains developed that reduced both α_a and α_c as observed (Table 1). This conclusion also partially explains why the agreement between the TEC values obtained from dilatometry and those measured using XRD is reasonable for most of the MAX phases, but not for Cr_2GeC and Nb_2AsC [39]. With an α_a of $2.9 \times 10^{-6} \text{ K}^{-1}$ and an α_c of $10.6 \times 10^{-6} \text{ K}^{-1}$, Nb_2AsC has a very high degree of anisotropy in thermal expansion. Said otherwise, the larger the TECs, the larger the difference one would expect between the TECs measured on a powder and those measured on bulk samples, whether by diffraction techniques or dilatometry.

It is generally considered that the MAX phases can form isostructural solid solution on all sites. It is then assumed that a random solid solution is obtained irrespective of site although it has been proposed that some ordering could occur on the X sites in $\text{Ti}_2\text{Al}(\text{C}_x\text{N}_{1-x})$ but with a small ordering energy so that it is generally not observed experimentally [50]. It is therefore likely the same for our case and our XRD results can be simply explained assuming a random solid solution on the A site. Furthermore, it was not necessary to introduce microstrains to fit the data during Rietveld refinement of the diffractograms, a result which is consistent with the absence of compositional or strain gradients in our samples.

The linear evolution of a , c and c/a , with increasing Al content (Fig. 2c) is not a general trend in MAX phases even if it is also the case for $(\text{Ti}_{1-x},\text{V}_x)_2\text{AlC}$ and $(\text{V}_{1-x},\text{Cr}_x)_2\text{AlC}$ solid solutions [24]. For instance, the a lattice parameter varies linearly as a function of x in $\text{Ti}_2\text{Al}(\text{C}_x\text{N}_{1-x})$ [25] but not the c lattice parameter. Neither a nor c vary linearly with x for $(\text{Ti}_{1-x},\text{Cr}_x)_2\text{AlC}$ compounds [24]. Therefore, there are no general simple rules or empiric laws that predict the evolution of the lattice parameters. What should obey Vegard's law in MAX-phase solid solutions is the interatomic distance between the elements, as is the case here. There is no other systematic study of the evolution of the z parameter in MAX-phase solid solutions, so general conclusions cannot be drawn on this point. In the present case, knowledge of the evolution of the z parameter is of interest since it allows following the evolution of the interatomic distance between the different atomic species. Based on this analysis and the results in Fig. 2f, the following conclusions can be reached: the Cr-C interatomic distance does not depend on x in the $\text{Cr}_2(\text{Al}_x,\text{Ge}_{1-x})\text{C}$ compounds whereas the distance between Cr and A atoms progressively increases with x . This is expected since the M-A bonds are generally weaker than the M-X ones; the strong M-X bond is not very sensitive to A modifications in solid solutions.

In general, TECs are intimately related to the interatomic bond strengths. In the frame of previous considerations, one should immediately propose that the thermal expansion of the Cr-C interatomic bonds should be lower than those of the Cr-A ones. Nevertheless, the knowledge of the TECs for the interatomic bondings (α_{Cr-C} and α_{Cr-A} where A = Al or Ge in the present case) cannot be simply deduced from α_a and α_c since they depend on the z parameter, which changes with temperature, as in the following general expressions:

$$\alpha_{M-A} = \frac{1}{d_{M-A}^2} \left(\frac{a^2}{3} \alpha_a + c^2 \left(z_M - \frac{1}{4} \right)^2 \left(\alpha_c + \frac{z_M}{z_M - \frac{1}{4}} \alpha_{z_M} \right) \right), \quad (\text{eq. 5})$$

$$\alpha_{M-X} = \frac{1}{d_{M-X}^2} \left(\frac{a^2}{3} \alpha_a + c^2 z_M^2 (\alpha_c + \alpha_{z_M}) \right), \quad (\text{eq. 6})$$

where

$$\alpha_{z_M} = \frac{1}{z_M} \frac{\partial z_M}{\partial T}, \quad (\text{eq. 7})$$

and M, A and X represent atomic species from a $M_{n+1}AX_n$ phase with $n = 1$.

In this work, α_a and α_c are known, whereas α_{z_M} would ideally be deduced from the refinement of the z parameter as a function of the temperature T . However, the small 2θ range chosen, as well as the quite high acquisition rates required at high temperatures to minimize the effects of thermal drift did not allow for the precise determination of z_M as a function of T . However, the fact that the intensity

ratios of the different diffraction peaks did *not* vary with increasing T is taken as evidence that the relative position of the Cr atoms in the unit cell, i.e. z , remains essentially constant or varies only slightly with increasing temperature. This is supported by preliminary neutron-diffraction results on Cr_2GeC indicating that the value of α_{z_M} is close to $-6 \cdot 10^{-6} \text{ K}^{-1}$ [51]. This value leads to a change of 4×10^{-4} for z_{Cr} between room temperature ($z_{\text{Cr}} = 0.0844$) to 800°C ($z_{\text{Cr}} = 0.084$). Such small variations are below the resolution of our experiment. Note that even such a small change in z induces strong modifications for the $\alpha_{\text{Cr-C}}$ and $\alpha_{\text{Cr-A}}$ values. In other words, it is not possible to unambiguously discuss the evolution of $\alpha_{\text{Cr-C}}$ and $\alpha_{\text{Cr-A}}$ as a function of the Al content without a precise determination of $\alpha_{z_{\text{Cr}}}$ for every composition. Similarly, it is not possible to calculate the evolution of the distortion parameters O_d and P_d with temperature. Nevertheless, by considering values of 10^{-5} K^{-1} for $\alpha_{z_{\text{Cr}}}$, it is possible to conclude that these distortion parameters remain very close to the values obtained at room temperature.

Despite these limitations (i.e. we cannot fully discuss the evolution of the Cr-A and Cr-C interatomic distance with the temperature), room temperature observations show that Cr-C bonds are weakly influenced by the Cr-Al or Cr-Ge bonds. It is then reasonable to propose that the Cr-Al bonds are stronger than the Cr-Ge bonds. This important conclusion is consistent with the following facts:

- a) The thermal expansion along [001] in Cr_2AlC is lower than in Cr_2GeC (Fig. 3c)
- b) At $\approx 285 \text{ GPa}$, the Young's modulus of Cr_2AlC [52,53,54] is significantly higher than that of Cr_2GeC at 245 GPa [55].
- c) The shear modulus of Cr_2AlC is reported to be 102 GPa [56], 116 GPa [53], and 121 GPa [57]. Even though there is some spread in these experimental data, it is clear that the shear modulus of Cr_2AlC is significantly higher than that of Cr_2GeC at $\approx 80 \text{ GPa}$ [55].

This conclusion is apparently at odds with bulk moduli, B , results. At 166 GPa, the bulk modulus of Cr_2AlC [56], is equal to or lower than that reported for Cr_2GeC (169 GPa [58] to 182 GPa [59]). The reason for this observation is unclear, but might be related to the presence a significant concentration of point defects on one of the Cr_2AlC sublattices. An indirect support of this conclusion is that the Young's modulus measured for Cr_2AlC in Ref. [56] is significantly lower than other reports [53,57] on the same material.

It should also be stressed that care must be taken when comparing experimental results on bulk and shear moduli with theoretical calculations of these parameters. Most theoretical studies on MAX phases [60,61,62,63] do not account for magnetism or strong electron-correlation effects, assumptions that are valid for MAX phases with M elements from group 4 or 5 (e.g., Ti, Nb, V). Neglecting these effects, however, strongly affect the results for the Cr-based MAX phases [41,64,65].

Lastly, we are faced with the following paradox. At 2.656 Å, the Cr-Al bond is longer than the C-Ge bond at 2.632 Å. Typically, bond distances cannot be directly related to bond strengths, lengths, etc. because the atomic radii of the elements generally differ. It is thus crucial, and fundamental, to the foregoing discussion to note that at 1.25 Å, the radii of the Al and Ge atoms are *identical*. It follows that, based on bond-length criteria alone, one would expect the Cr-Al bond to expand faster with increasing temperature, when in fact it does not (Fig. 3c). This implies that other factors, such as the distortion of the octahedra or trigonal prisms, come into play. Clearly more work is needed, both theoretical and experimental, to resolve this interesting paradox.

V. Summary and Conclusions

Using XRD and Rietveld analysis we have determined the lattice parameters as a function of x and temperature for $\text{Cr}_2(\text{Al}_x\text{Ge}_{1-x})\text{C}$ compounds including the two end members. At room temperature, the a and c lattice parameters and the c/a ratio vary linearly with x . Whereas the Cr-A interatomic distance increases with x ($A = \text{Al}$ and/or Ge), the length of the Cr-C interatomic bonding remains constant. With increasing Al-content, the thermal expansion along the a direction is essentially constant at about $14 \pm 1 \cdot 10^{-6} \text{ K}^{-1}$. The c lattice-parameter thermal expansion, on the other hand, decreases monotonically from $17 \pm 1 \cdot 10^{-6} \text{ K}^{-1}$ to about $12 \pm 1 \cdot 10^{-6} \text{ K}^{-1}$ with increasing Al content.

The most important result of this work is the demonstration of compositional tuning of the thermal expansion coefficients so as to render them virtually isotropic for the $\text{Cr}_2(\text{Al}_{0.75}\text{Ge}_{0.25})\text{C}$ composition. This compound should thus respond to temperature variations like a cubic solid, which has the key benefit of absence of residual stresses at room temperature when cooling from higher temperatures.

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Table 1: Summary of room temperature lattice parameters and thermal expansion coefficients of compounds explored in this work. Also included are previously reported values.

Compound	a (Å)	c (Å)	α_a (K) ⁻¹ x10 ⁻⁶	α_c (K) ⁻¹ x10 ⁻⁶	$(2\alpha_a+\alpha_c)/3$ x10 ⁻⁶	Ref.
Cr₂GeC	2.9529	12.110	14.3	17.2	15.27	This work
			12.9	17.6	14.47	Scabarozi et al. [39]
			12.3	14.4	13.00	Lane et al. [40]
Cr₂(Al_{0.25}Ge_{0.75})C	2.9396	12.212	14.8	15.7	15.00	This work
Cr₂(Al_{0.5}Ge_{0.5})C	2.9091	12.437	13.4	14.8	13.87	This work
Cr₂(Al_{0.75}Ge_{0.25})C	2.8796	12.646	13.4	13.0	13.27	This work
Cr₂AlC	2.862	12.817	13.3	11.7	12.77	This work
			12.8	12.1	12.57	Scabarozi et al. [39]
Cr₅Ge₃C_x	7.14	4.88	16.3	28.4	20.3	This work
	7.6	4.86				Scabarozi, thesis [43]

Table 2: Structural parameters of Cr₅Ge₃C_x.

Atom	Site	x	y	z	Occupancy
Cr(1)	4d	1/3	2/3	0	1
Cr(2)	6g	0.237	0	1/4	1
Ge	6g	0.6	0	1/4	1
C	2b	0	0	0	1
Space group : P6 ₃ /mcm (n°193)					
a= 7.14 Å					
c= 4.88 Å					

Figure captions

Figure 1 : X-Ray diffractograms obtained at room temperature for $\text{Cr}_2\text{Al}_x\text{Ge}_{1-x}\text{C}$ compounds. The residual of the refinement, i.e., the difference between the experimental diffractogram and that deduced from Rietveld refinement is given below every diffractogram.

Figure 2 : In $\text{Cr}_2\text{Al}_x\text{Ge}_{1-x}\text{C}$ compounds, evolution as a function of the Al content (x) of the a and c lattice parameters ((a) and (b) respectively), the relative change of a , c , c/a and the unit cell volume (c), the height of the Cr atom z_{Cr} in the unit cell (d), the distortion factors O_d and P_d (e). the relative change of the distance between Cr atoms and A (Al and/or Ge) atoms or C atoms (f).

Figure 3: Evolution of the a and c lattice parameters, (a) and (b), as a function of the temperature. Deduced linear thermal expansion coefficients along the a and c axis (α_a and α_c) are given in (c).

Figure 4: Evolution of the a and c lattice parameters of $\text{Cr}_5\text{Ge}_3\text{C}_x$ as a function of temperature

Figure 1
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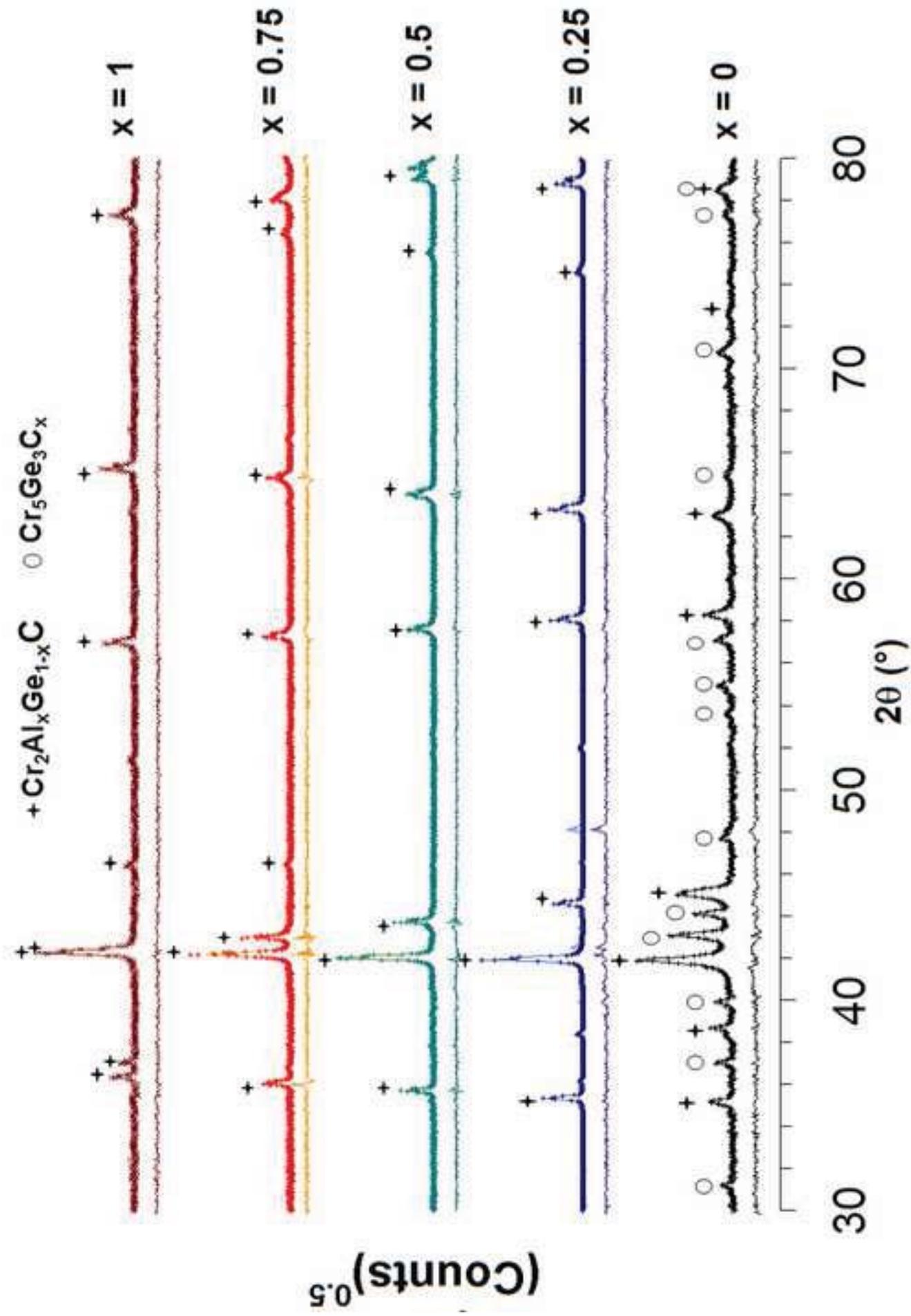
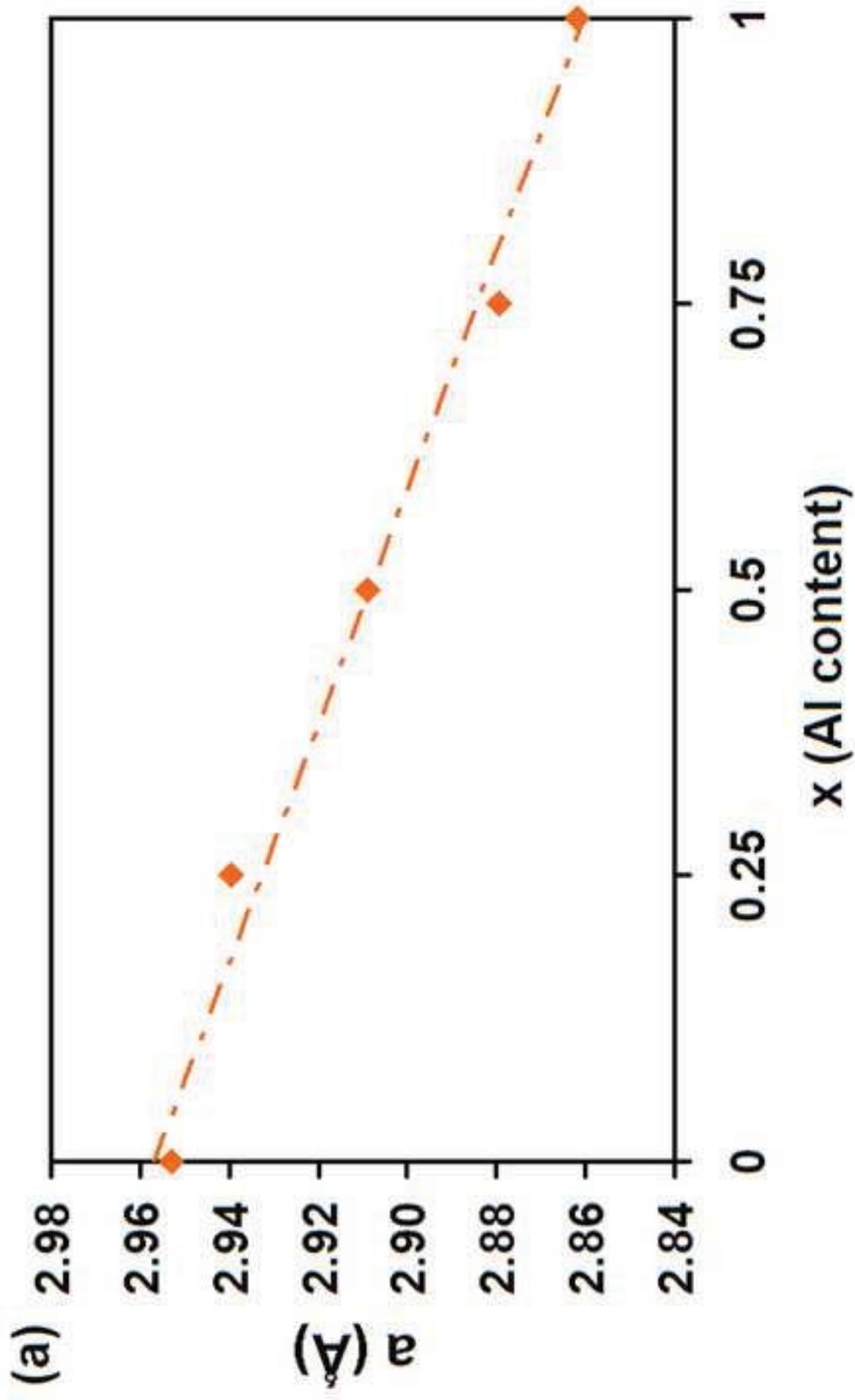


Figure 2a
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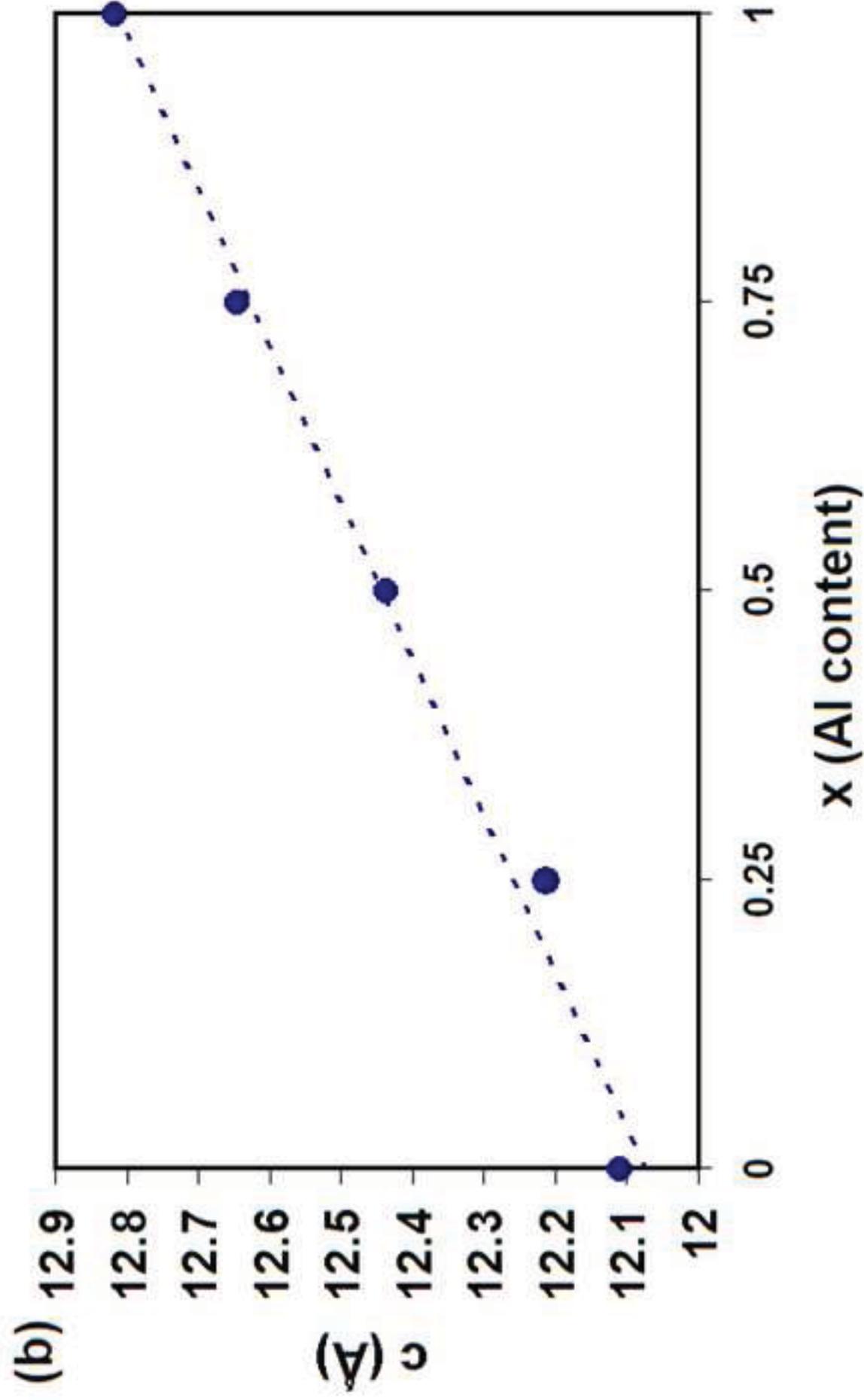
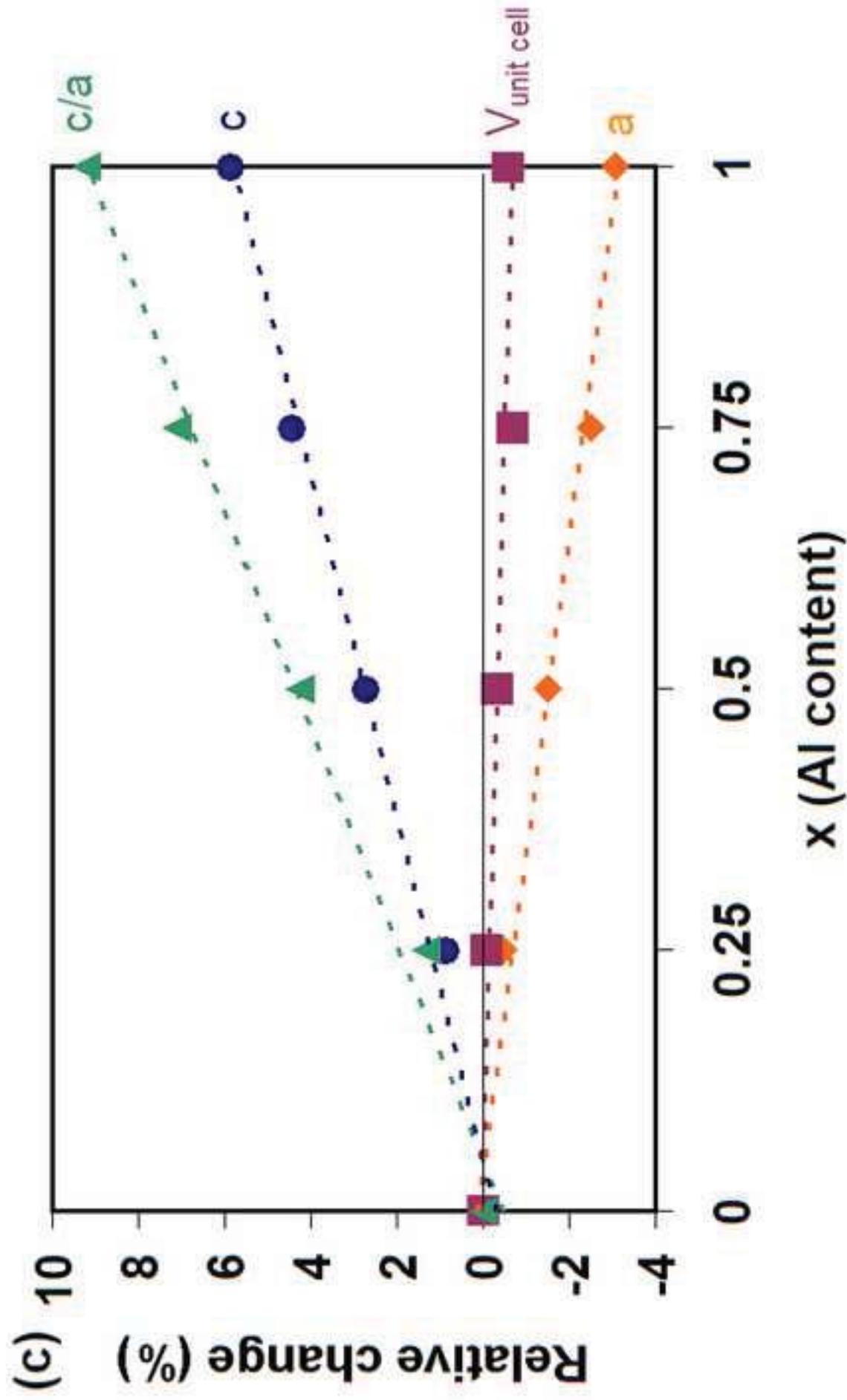
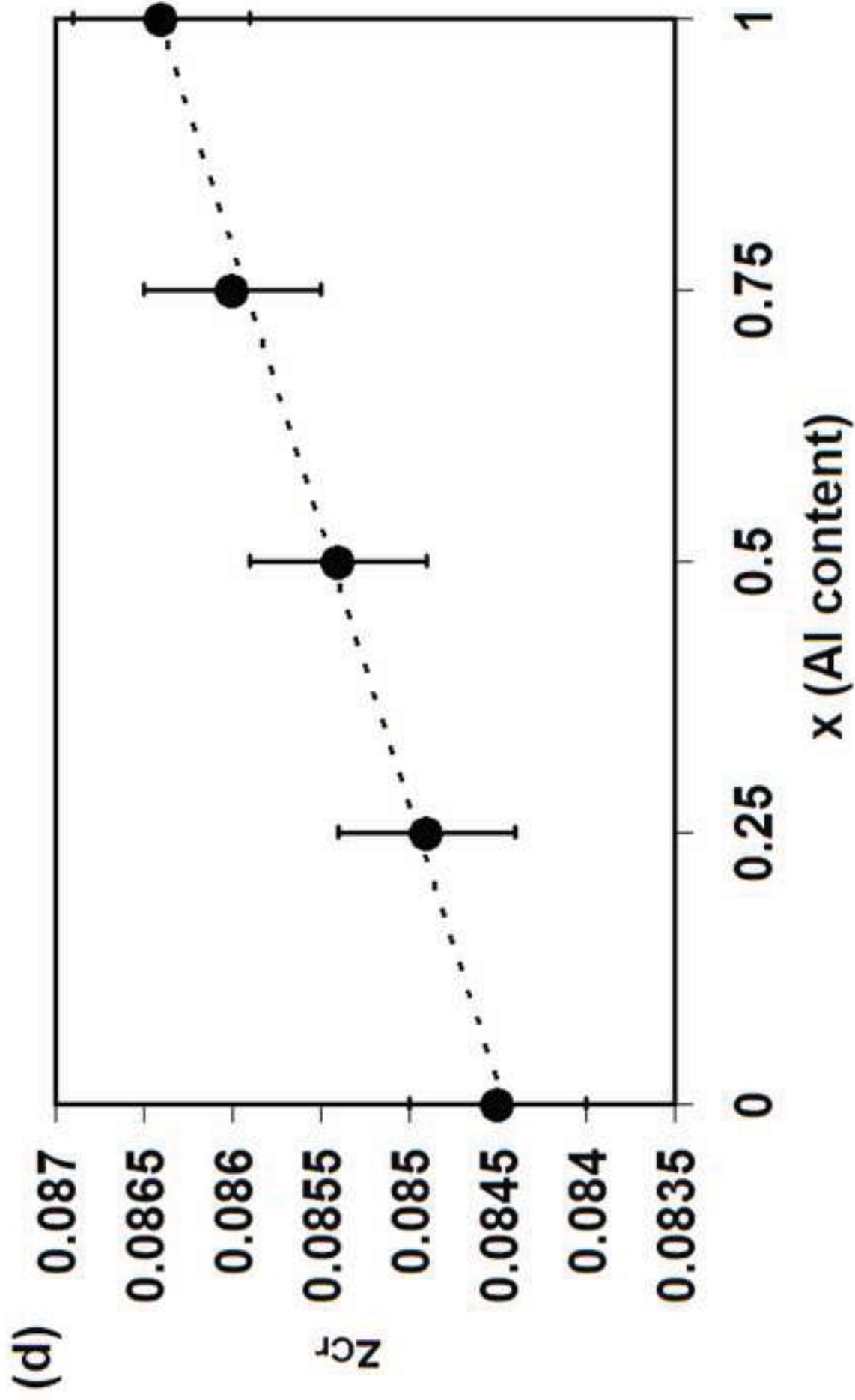


Figure 2c
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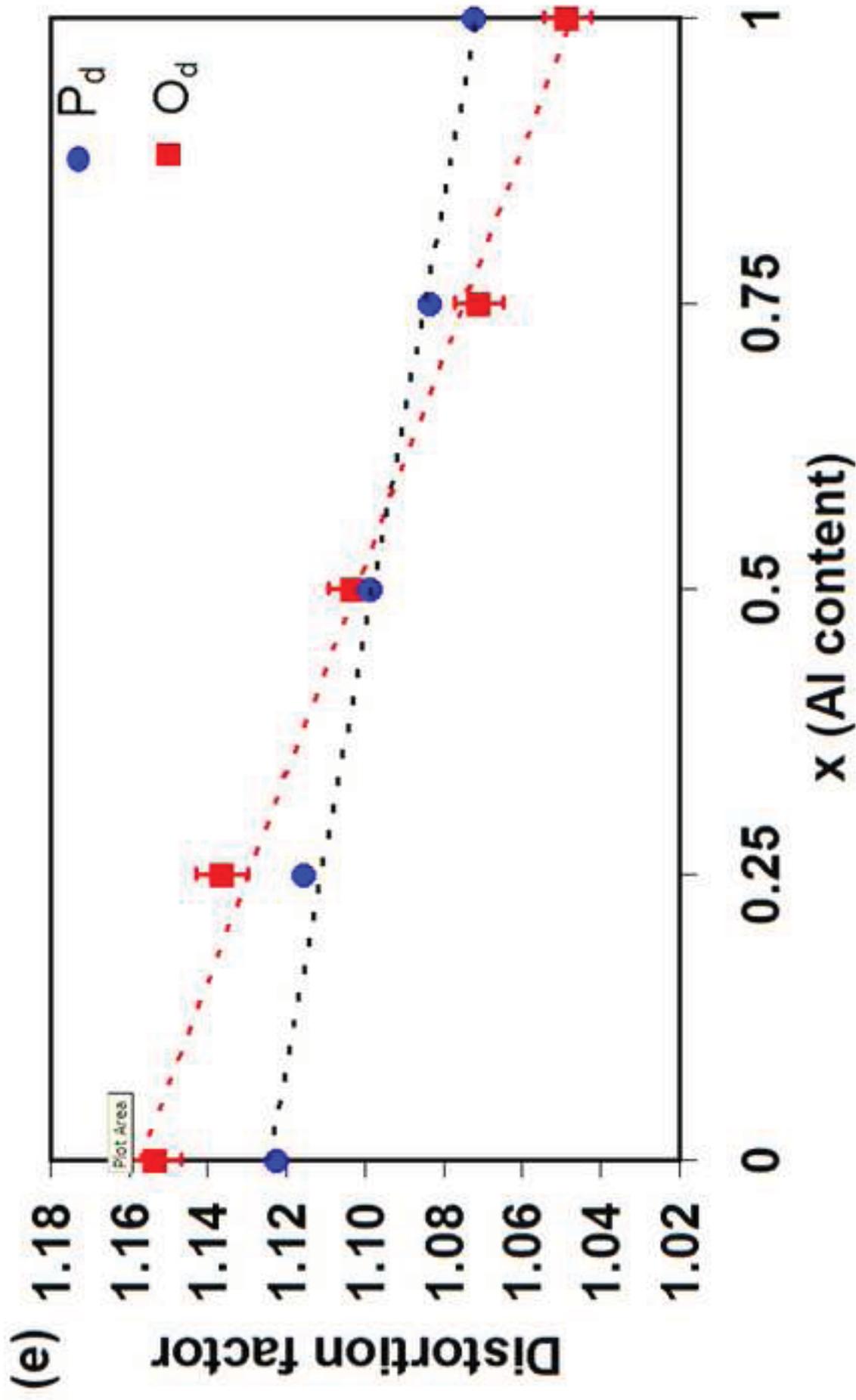


Figure 2f
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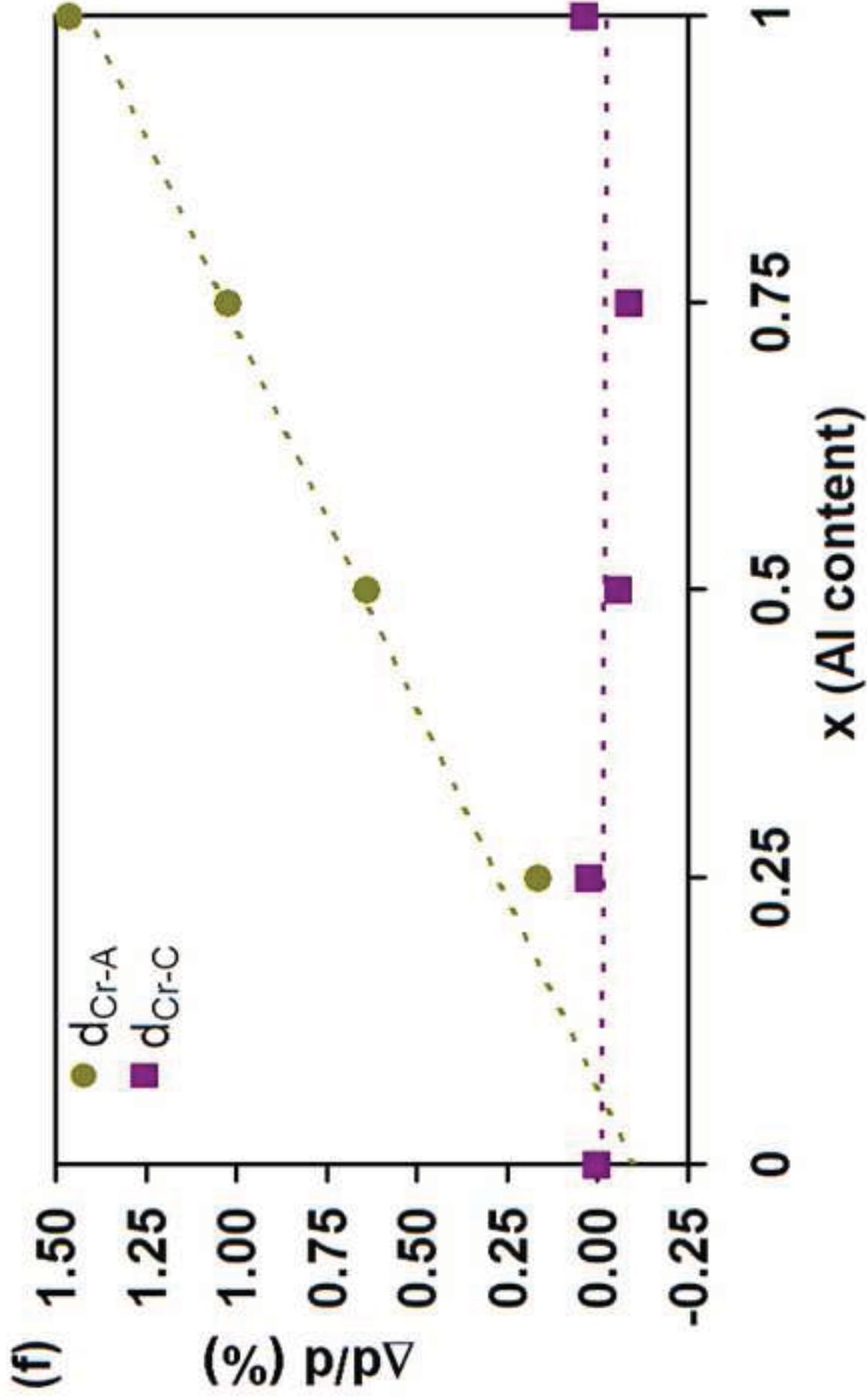


Figure 3a
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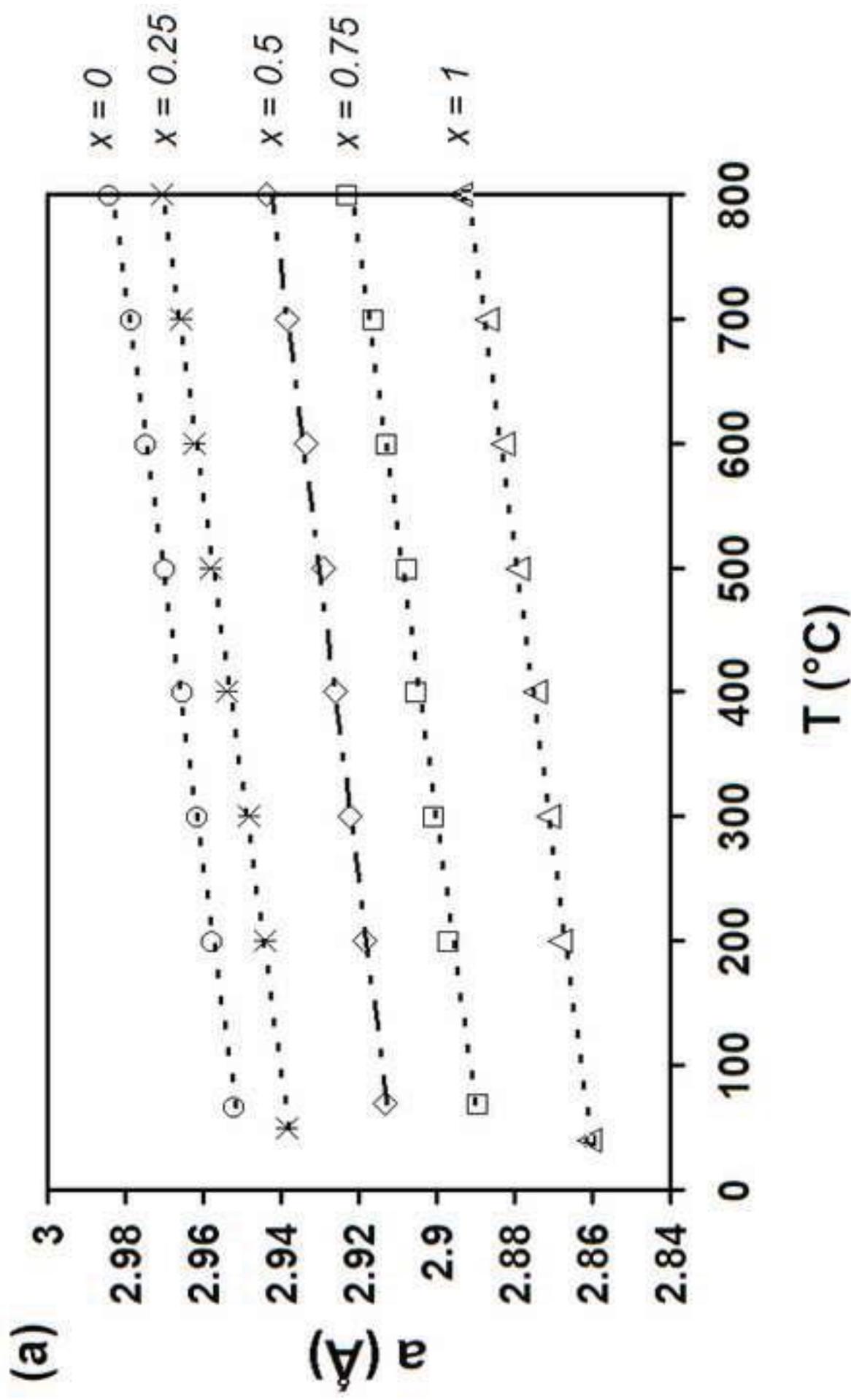
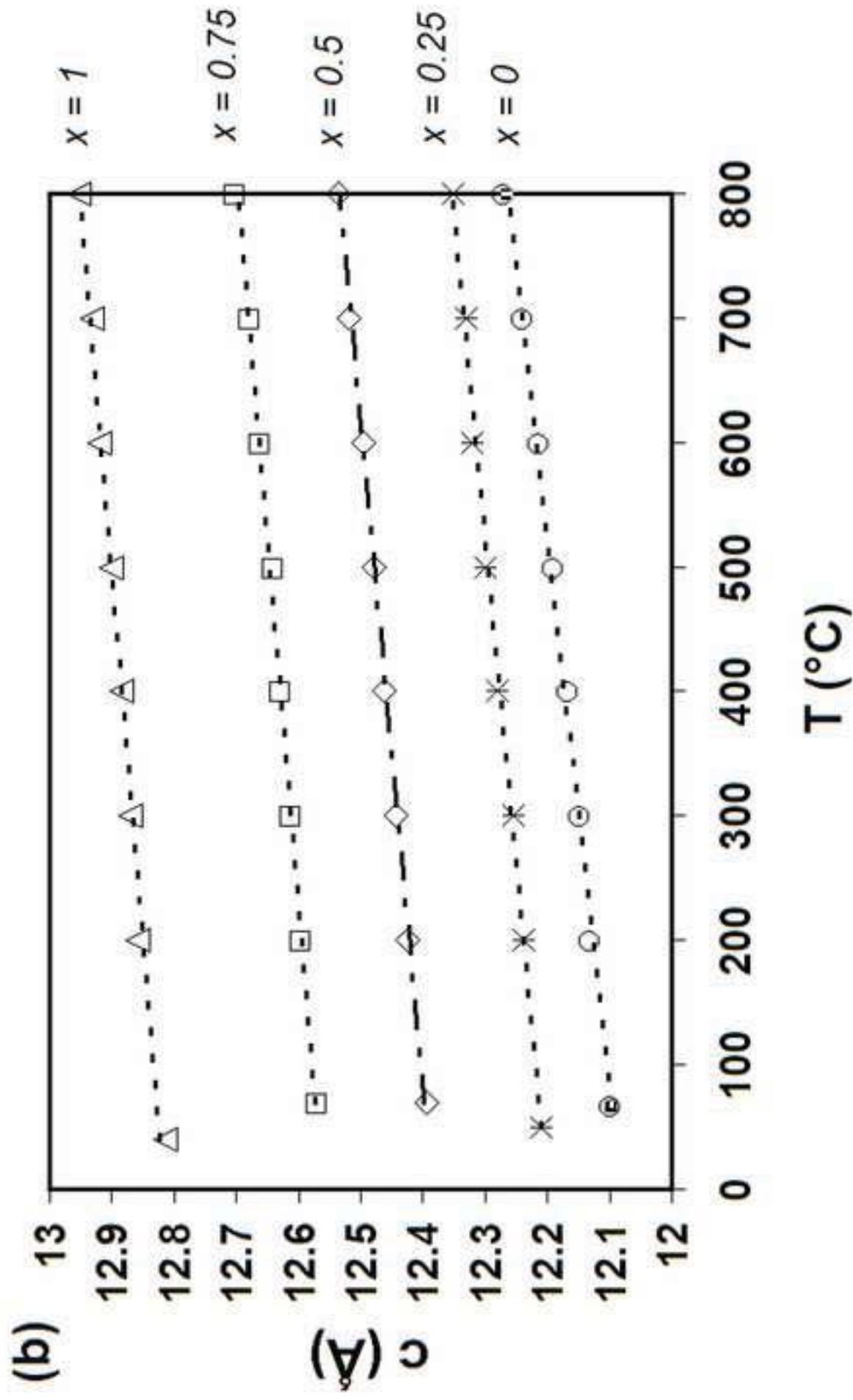


Figure 3b
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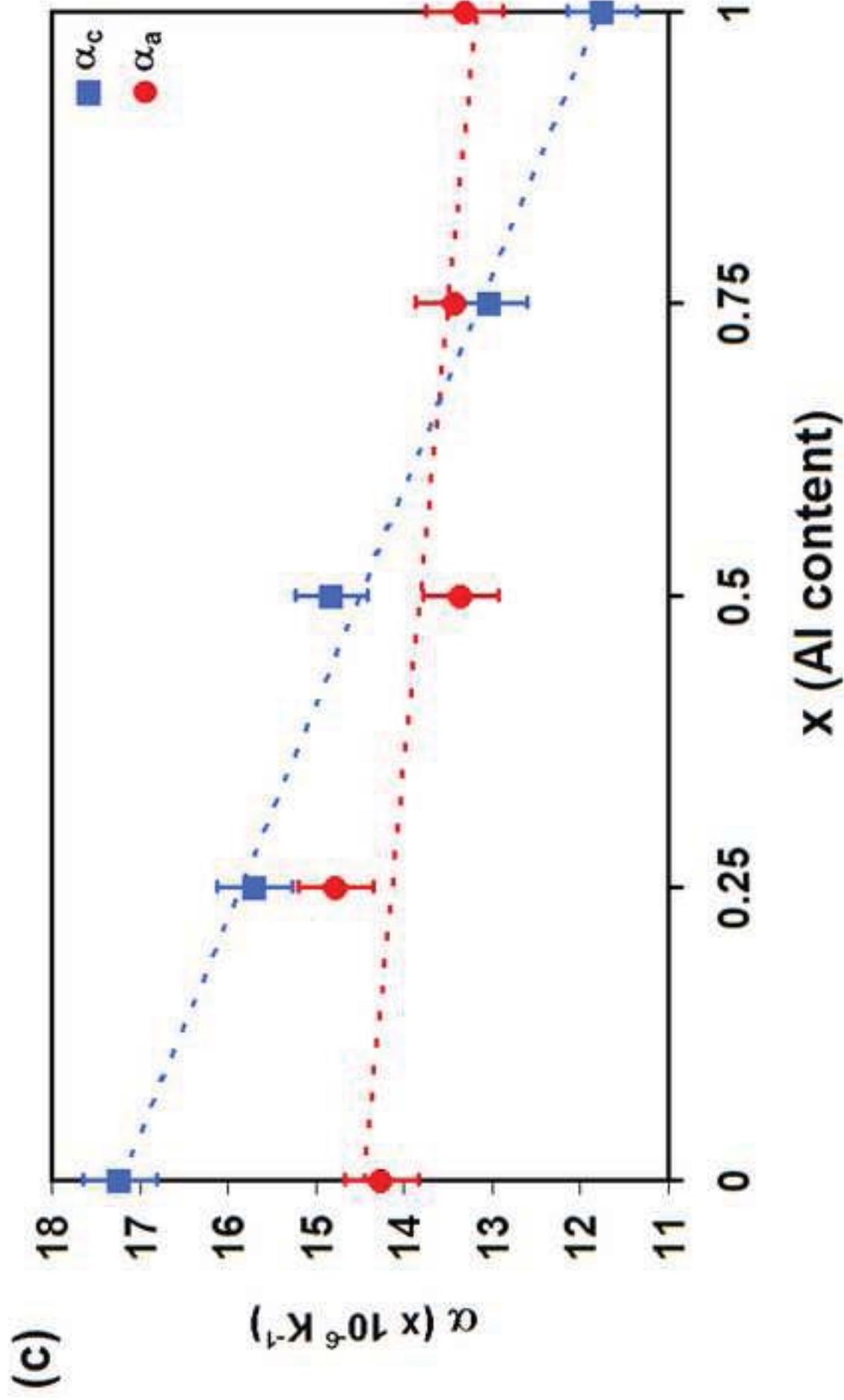


Figure 4
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